

Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it contains a valid OMB control number.

Substitute for form 1449A/PTO				Complete if Known	
				Application Number	10/797,231
				Filing Date	March 10, 2004
				First Named Inventor	Matthew T. Currie
				Art Unit	2812
				Examiner Name	A. G. Ghyka
Sheet	1	of	2	Attorney Docket Number	ASC-057C1

U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No.*	Document Number Number-Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
A70*	US-5,166,084	11-24-1992	Pflester		
A71*	US-5,212,110	05-18-1993	Pflester et al.		
A72*	US-5,981,400	11-09-1999	Lo		
A73*	US-6,074,919	06-13-2000	Gardner et al.		
A74*	US-6,103,559	08-15-2000	Gardner et al.		
A75*	US-6,154,475	11-28-2000	Soref et al.		
A76*	US-6,162,688	12-19-2000	Gardner et al.		
A77*	US-6,191,432	02-20-2001	Sugiyama et al.		
A78*	US-6,194,722	02-27-2001	Fiorini et al.		
A79*	US-6,210,988	04-03-2001	Howe et al.		
A80*	US-6,218,677	04-17-2001	Broekaert		
A81*	US-6,583,015-A1	06-24-2003	Fitzgerald et al.		
A82*	US-6,846,715	01-25-2005	Fitzgerald et al.		
A83*	US-7,217,668	05-15-2007	Fitzgerald et al.		
A84*	US-20050003229	01-06-2005	Bedell et al.		
A85*	US-20070082470	04-12-2007	Fitzgerald et al.		

FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No.*	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages Or Relevant Figures Appear	T ⁴
		Country Code ³ -Number ⁴ -Kind Code ⁵ (if known)				
B1	EP-0 587 520		03-16-1994			✓
B2	JP-2000-031491		01-28-2000			✓

Examiner Signature	Date Considered
--------------------	-----------------

*EXAMINER Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. *CITE NO.: Those application(s) which are marked with an single asterisk (*) next to the Cite No. are not supplied (under 37 CFR 1.98(a)(2)(iii)) because that application was filed after June 30, 2003 or is available in the IWF. Applicant's unique citation designation number (open parenthesis). See Kind Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. *Enter Office that issued the document, by the two-letter code (WIPO Standard ST:16). For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ² Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST:16 if possible. ³ Applicant is to place a check mark here if English language Translation is attached.

Substitute for form 1449/PTO

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

(Use as many sheets as necessary)

Sheet

2

of

2

Complete if Known

Application Number	10/797,231
Filing Date	March 10, 2004
First Named Inventor	Richard Hammond
Art Unit	2812
Examiner Name	A. G. Ghyka
Attorney Docket Number	ASC-057C1

NON PATENT LITERATURE DOCUMENTS

Examiner Initials	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
	C86	Abramo, A. et al., "Mobility Simulation of a Novel Si/SiGe FET Structure," IEEE Electron Device Letters, vol. 17, no. 2, February 1996, pp. 59-61.	
	C87	Hellberg, P.E. et al., "Oxidation of silicon-germanium alloys. I. An experimental study," Journal of Applied Physics, vol. 82, no. 11, December 1, 1997, pp. 5773-5778.	
	C88	International Search Report for Patent Application No. PCT/US 01/24614, dated 3/11/2002, 3 pages.	
	C89	Notice of Assignment of Inter Partes Reexamination Request, Patent No. 6,846,715, July 27, 2006.	
	C90	Office Action in Inter Partes Reexamination, Patent No. 6,846,715, August 30, 2006.	
	C91	Niino, T. et al., "SiGe Passivation for Si MBE Regrowth," Japanese Journal of Applied Physics, vol. 29, no. 9, pp. 1702-1704, September 1990.	
	C92	O'Neill, A.G. et al., "Deep Submicron CMOS Based on Silicon Germanium Technology," IEEE Transactions on Electron Devices, vol. 43, no. 6, June 1996, pp. 911-918.	
	C93	Order Granting/Denying Request for Inter Partes Reexamination, Patent No. 6,846,715, August 30, 2006.	
	C94	Request for Inter Partes Reexamination of U.S. Patent No. 6,846,715, June 26, 2006.	
	C95	Wolf, "Silicon Processing for the VLSI Era, vol. 2: Process Integration," pp. 27, 331 (Lattice Press, 1990).	
	C96	Wu et al., "High-Quality Thermal Oxide Grown on High-Temperature-Formed SiGe," 147 J. Electrochemical Soc'y 5, pp. 1962-64 (2000).	

Examiner Signature	Date Considered
--------------------	-----------------

¹EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

²Applicant's unique citation designation number (optional). ³Applicant is to place a check mark here if English language Translation is attached.